

SiPM single photon time resolution measured via bi-luminescence

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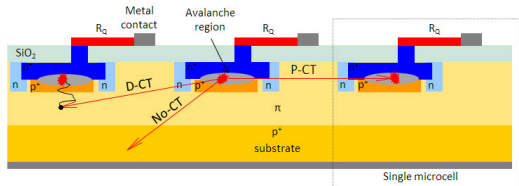
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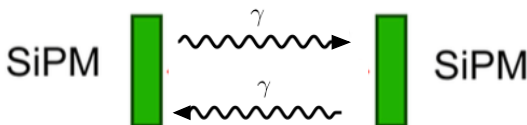
- ▶ Silicon photomultipliers (SiPM) have found widespread use in scientific experiments
 - From HEP to Medical Science
- ▶ Characterization of such devices include:
 - Breakdown Voltage
 - Cross-talk probability
 - Dark Count Rate
 - Photon detection efficiency
 - Single Photon Timing Resolution (SPTR)
- ▶ Some measurements are easy, some require more advanced equipment
 - e.g. measuring the SPTR usually requires external laser sources
- ▶ Can we measure the SPTR without the need fancy equipment?
Yes, via bi-luminescence!

Cross-talk and bi-luminescence

- ▶ During an avalanche, some electrons recombine producing secondary photons
- ▶ These photons can enter a neighboring cell, causing additional avalanches (Optical Cross-talk)
- ▶ Bi-luminescence refers to the process where one or more of these photons leaves the device and causes an avalanche in a neighboring device
- ▶ Our light detector is actually a light source
→ Can use as a source to measure single photon events

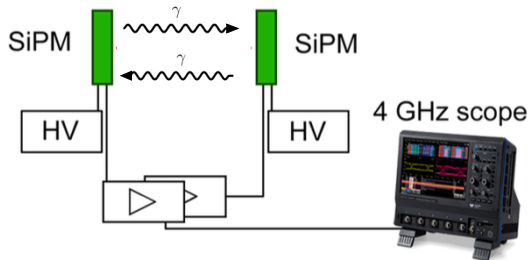
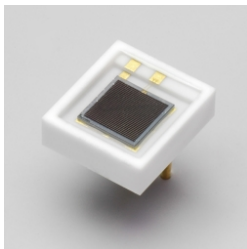


[courtesy of Hamamatsu Photonics]



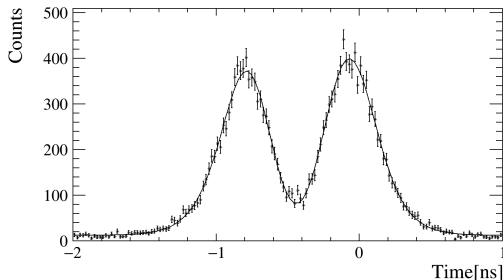
Set-up

- ▶ 2x HPK S13360-3050CS ($3 \times 3 \text{ mm}^2$ area, $50 \text{ }\mu\text{m}$ pitch)
- ▶ Each connected to custom amplifier boards and a HV source
- ▶ Signals recorded with a 4-ch 4 GHz oscilloscope
- ▶ Set-up is housed in a freezer (not the scope!) flushed with dry air allowing for T as low as -30°C
- ▶ Waveforms are timestamped using a CFD method (optimized at 24%)



The model

- ▶ The resulting $\Delta t = t_1 - t_2$ distribution shows a double peaked structure
- ▶ Each peak can be described by a gaussian convoluted with an exponential
- ▶ The Gaussian term includes contributions from emission and absorption ($\sim \sqrt{2} \times \text{SPTR}$)
- ▶ Exponential term arises from uncertainty in the time of emission due to afterpulsing



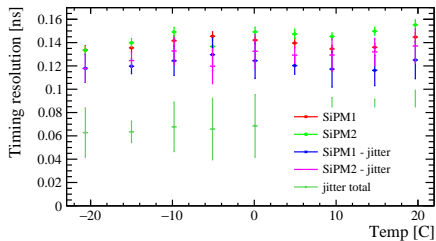
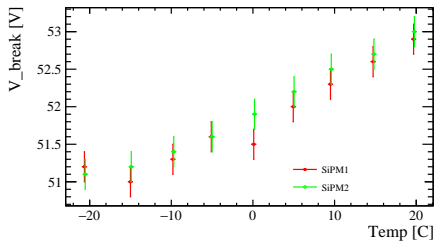
$$f(\Delta t; \mu, \sigma, \lambda) \propto e^{\frac{\lambda}{2}(2\mu + \lambda\sigma^2 - 2\Delta t)} \operatorname{erfc}\left(\frac{\mu + \lambda\sigma^2 - \Delta t}{\sqrt{2}\sigma}\right)$$

σ : Uncertainty from emission and absorption process

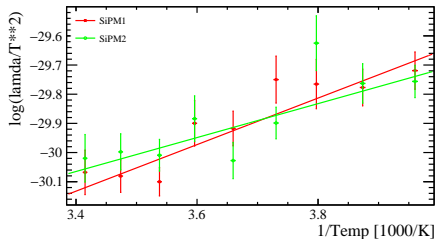
μ : Mean of the gaussian

λ : Afterpulse rate

Results



- ▶ Measurements carried out from -20 to +20 ° C, $OV = +3 V$
- ▶ $SPTR(20^{\circ}C) = 145/\sqrt{2} = 103 \pm 3 \text{ ps}$
→ Const vs. T
- ▶ $\lambda(20^{\circ}C) = 7.5 \pm 0.5 \text{ GHz}$
- ▶ Arrhenius plot used to extract energy of defect responsible for λ
 $\Delta E_1 = E_c - E_1 = 0.07 \pm 0.01 \text{ eV}$
 $\Delta E_2 = E_c - E_2 = 0.05 \pm 0.01 \text{ eV}$



- ▶ The SPTR of SiPMs is an important characterization parameter
- ▶ We present a simple method of measuring the SPTR using bi-luminescence
- ▶ Δt distribution modeled with a Gaussian convoluted with an exponential
→ accounts for afterpulsing
- ▶ SPTR ~ 100 ps, similar to literature values
- ▶ Afterpulse rate $\sim 7\text{-}8$ GHz
→ $\Delta E = 0.05 - 0.07$ eV

BACKUP

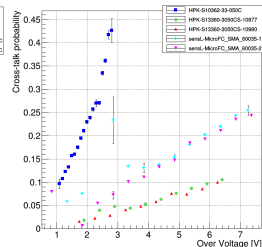
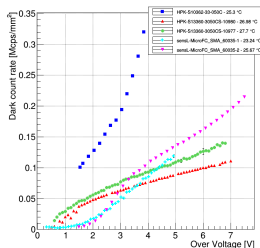
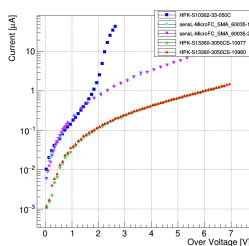
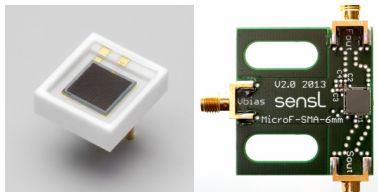
SiPM characterization

- ▶ SiPMs from two manufacturers:

Hamamatsu Photonics
SensL

- ▶ SiPM characterized by:

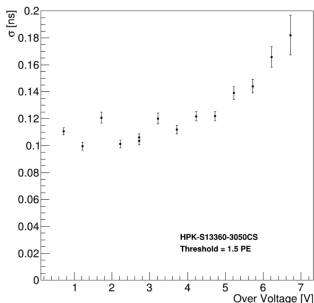
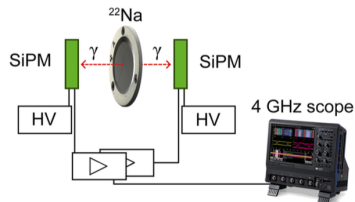
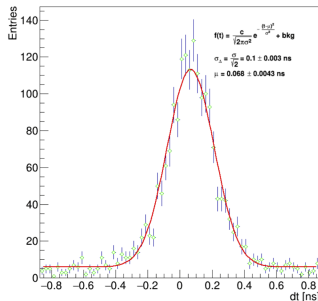
Current-Voltage behavior
Dark count rate
Cross-talk probability
Single photon time resolution



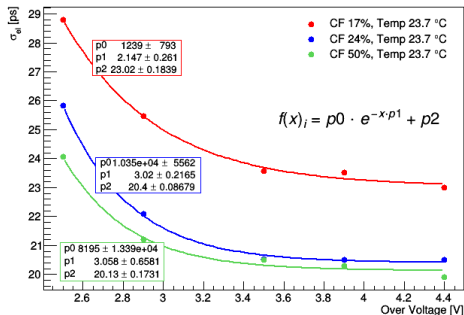
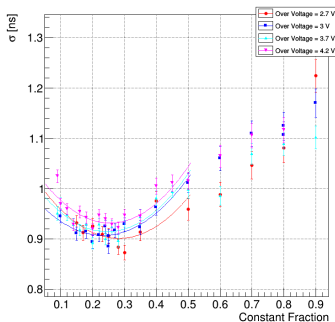
SiPM single photon time resolution

- ▶ Back-to-back γ s from pair-annihilation in ^{22}Na is used as a source
- ▶ Single photon time resolution is taken as the Gaussian width in the time difference spectrum from coincidence signals
- ▶ Very good resolution ~ 100 ps is observed in 3×3 mm HPK SiPM

2.7 V - 1.5 photon level

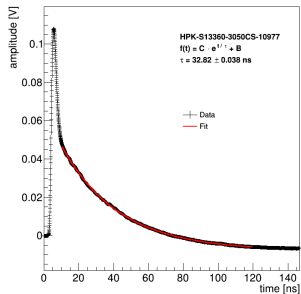
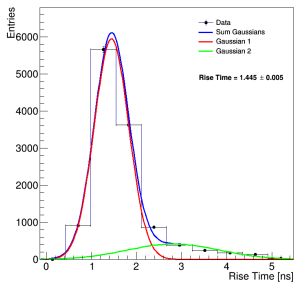
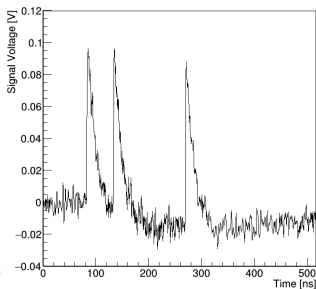
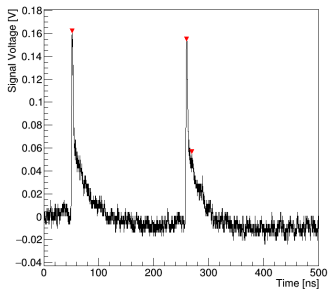


CFD optimization and electronic noise



- Scan of CFD threshold indicated an optimal value of 24%
- Electronic noise at this value is $\sigma_{el} = 22$ ps for the optimal $OV = 3$ V

Waveforms, rise time and decay time



DCR and cross talk

